

Publikationen

(2013): Scanning probe microscopy based electrical characterization of thin dielectric and organic semiconductor films. In: 24th European Symposium on Reliability of Electron Devices, Failure Physics and Analysis (ESREF), Arcachon, Frankreich.

(2013): Scanning probe microscopy based electrical characterization of thin dielectric and organic semiconductor films. In: Microelectronics Reliability, vol. 53, no. 9-11, pp. 1430-1433.

(2011): Capacitance and Conductivity Mapping of Organic Films and Devices with Non-Contact SPM Methods. In: International Workshop on Scanning Probe Microscopy for Energy Applications, Mainz.